AMENDMENTS TO THE CLAIMS

Please amend the claims as follows. Please cancel claims 1-5 and 16-36. Claim 6 has been amended. Claims 37-56 have been added. No new matter has been added. A complete listing of the current pending claims is provided below and supersedes all previous claims listing(s).

- 1-5. (Canceled)
- 6. (Currently Amended) A method for generating a lithography mask, comprising: generating integrated circuit design data;

analyzing the integrated circuit design data to generate context information for features of a mask without the use of tags;

configuring mask design data to emphasize the context and priority of the features in the mask design based on the context information; and

using the context information to write the mask features.

7. (Previously Presented) The method of claim 6, wherein using context information comprises:

analyzing the mask features for contextual priority.

- 8. (Original) The method of claim 7, wherein using context information comprises: assigning priorities to the mask features.
- 9. (Original) The method of claim 8, wherein assigning priorities to the mask features comprises:

applying criteria to mask design data by manual process.

10. (Original) The method of claim 8, wherein assigning priorities to the mask features comprises:

applying criteria to mask design data by computer-aided automated process.

11. (Previously Presented) The method of claim 6, wherein using context information comprises:

analyzing mask features to determine circuit elements expected to be produced by a lithography system at a chip wafer surface.

- 12. (Original) The method of claim 6, further comprising:
 configuring a mask design database to include additional contextual mask design data
 generated in using the contextual information from the integrated circuit design data.
- 13. (Previously Presented) The method of claim 12, further comprising: configuring the mask design database to optimize a write order for use by a mask writing system.
- 14. (Original) The method of claim 6, wherein using context information comprises: passing context information to a mask writing system.
- 15. (Original) The method of claim 6, wherein using context information comprises: controlling a mask writing system based on the context information.

16-36. (Canceled)

37. (New) An apparatus for generating a lithography mask, comprising: means for generating integrated circuit design data; means for analyzing the integrated circuit design data to generate context information for

features of a mask;

means for configuring mask design data to emphasize the context and priority of the features in the mask design based on the context information; and

- means for using the context information to write the mask features.
- 38. (New) The apparatus of claim 37, wherein means for using context information comprises: means for analyzing the mask features for contextual priority.
- 39. (New) The apparatus of claim 38, wherein means for using context information comprises: means for assigning priorities to the mask features.
- 40. (New) The apparatus of claim 39, wherein means for assigning priorities to the mask features comprises:

means for applying criteria to mask design data by manual process.

41. (New) The apparatus of claim 39, wherein means for assigning priorities to the mask features comprises:

means for applying criteria to mask design data by computer-aided automated process.

- 42. (New) The apparatus of claim 37, wherein means for using context information comprises: means for analyzing mask features to determine circuit elements expected to be produced by a lithography system at a chip wafer surface.
- 43. (New) The apparatus of claim 37, further comprising:

 means for configuring a mask design database to include additional contextual mask design data generated in using the contextual information from the integrated circuit design data.
- 44. (New) The apparatus of claim 43, further comprising:

 means for configuring the mask design database to optimize a write order for use by a mask writing system.
- 45. (New) The apparatus of claim 37, wherein means for using context information comprises: means for passing context information to a mask writing system.
- 46. (New) The apparatus of claim 37, wherein means for using context information comprises: means for controlling a mask writing system based on the context information.
- 47. (New) A computer program product comprising a computer usable medium having executable code to execute a process for generating a lithography mask, the process comprising: generating integrated circuit design data;

analyzing the integrated circuit design data to generate context information for features of a mask;

configuring mask design data to emphasize the context and priority of the features in the mask design based on the context information; and

using the context information to write the mask features.

48. (New) The computer program product of claim 47, wherein using context information comprises:

analyzing the mask features for contextual priority.

49. (New) The computer program product of claim 48, wherein using context information comprises:

assigning priorities to the mask features.

50. (New) The computer program product of claim 49, wherein assigning priorities to the mask features comprises:

applying criteria to mask design data by manual process.

51. (New) The computer program product of claim 49, wherein assigning priorities to the mask features comprises:

applying criteria to mask design data by computer-aided automated process.

52. (New) The computer program product of claim 47, wherein using context information comprises:

analyzing mask features to determine circuit elements expected to be produced by a lithography system at a chip wafer surface.

- 53. (New) The computer program product of claim 47, further comprising: configuring a mask design database to include additional contextual mask design data generated in using the contextual information from the integrated circuit design data.
- 54. (New) The computer program product of claim 53, further comprising: configuring the mask design database to optimize a write order for use by a mask writing system.
- 55. (New) The computer program product of claim 47, wherein using context information comprises:

passing context information to a mask writing system.

56. (New) The computer program product of claim 47, wherein using context information comprises:

controlling a mask writing system based on the context information.